



RADIO TEST REPORT

Test Report No. : 28HE0125-HO-01-A

Applicant : Sony Computer Entertainment Inc.
Type of Equipment : WIRELESS CONTROLLER
Model No. : CECHZC2U
FCC ID : AK8CECHZC2
Test regulation : FCC Part 15 Subpart C 2008
Section 15.207, Section 15.247
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.

Date of test:

March 18 and 19, 2008

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NVLAP LAB CODE: 200572-0

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*As for the range of Accreditation in NVLAP, you may refer to the WEB address, <http://uljapan.co.jp/emc/nvlap.htm>

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SECTION 1: Customer information

Company Name	Sony Computer Entertainment Inc.
Brand Name	SONY
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SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment	WIRELESS CONTROLLER
Model No	CECHZC2U
Serial No	1(Antenna Terminal Conducted test), 4(Radiated emission test)
Country of Manufacture	China
Receipt Date of Sample	March 18, 2008
Condition of EUT	Production prototype (Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT	No modification by the test lab.

2.2 Product Description

Model No: CECHZC2U is the WIRELESS CONTROLLER for game machine.

Product Specification

Clock frequency in the system	26MHz and 4MHz
Operating Temperature	5-35 deg. C
Power Supply	DC5V (USB Bus Power)
Battery Supply	DC3.7V
Size	93.7 x 157 x 62.3 mm
Weight	193 g

Radio Specification: Bluetooth (Ver. 2.0+EDR)

Equipment Type	Transceiver
Frequency of Operation	2402-2480MHz
Type of Modulation	FHSS (GFSK, $\pi/4$ DQPSK, 8DPSK)
Bandwidth & Channel spacing	1MHz & 1MHz
Method of frequency generation	Synthesizer
Power Supply (inner)	DC2.8V
Antenna Type	lambda /4 Inverted F Type
Antenna Gain	-0.1dBi max

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2008, final revised on March 24, 2008

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.247 Operation within the bands 902-928MHz,
2400-2483.5MHz, and 5725-5850MHz

*The revision on March 24, 2008 does not influence the test specification applied to the EUT.

FCC 15.31 (e)

The stable voltage (DC2.8V) is constantly supplied to RF Module. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.2 Procedures and results

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst Margin	Results
1	Conducted emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements	FCC: Section 15.207	-	N/A	N/A	N/A*1)
		IC: RSS-Gen 7.2.2	IC: RSS-Gen 7.2.2				
2	Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)	Conducted	N/A	See data.	Complied
		IC: -	IC: RSS-210 A8.1 (b)				
3	20dB Bandwidth	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)	Conducted	N/A		Complied
		IC: -	IC: RSS-210 A8.1 (a)				
4	Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)(iii)	Conducted	N/A		Complied
		IC: -	IC: RSS-210 A8.1 (d)				
5	Dwell time	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)(iii)	Conducted	N/A		Complied
		IC: -	IC: RSS-210 A8.1 (d)				
6	Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(b)(1)	Conducted	N/A	Complied	
		IC: RSS-Gen 4.6	IC: RSS-210 A8.4 (2)				
7	Band Edge Compliance	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(d)	Conducted	N/A	Complied	
		IC: -	IC: RSS-210 A8.5				
8	Spurious Emission	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators	FCC: Section 15.247(d)	Conducted/ Radiated	N/A	[Tx] 7.4dB, Vertical, 2483.5MHz, AV [Rx] 8.5dB, Vertical, 2439.6MHz, AV	Complied
		IC: RSS-Gen 4.7 RSS-Gen 4.8	IC: RSS-210 A8.5 RSS-Gen 7.2.1 and 7.2.3				

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15.

*1) The test is not applicable since the EUT is not connected with AC power during wireless communication. The EUT is connected with AC power at standby and Movement of Dual Shock Motors and Charging Battery modes. Please see UL Japan Test Report No. 28HE0125-HO-01-C for the test data at those two modes.

*These tests were performed without any deviations from test procedure except for additions or exclusions.

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

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3.3 Addition to standards

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied Band Width	RSS-Gen 4.6.1	RSS-Gen 4.6.1	Conducted	N/A	N/A	N/A

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission	Radiated emission (10m*)				Radiated emission (3m*)			Radiated emission (3m*)	
	150kHz-30MHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	1GHz-18GHz	18GHz-40GHz	
No.1 semi-anechoic Chamber (±)	3.7dB	3.1dB	4.7dB	4.4dB	3.2dB	3.7dB	4.4dB	5.9dB	6.1dB	
No.2 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.3dB	3.9dB	5.9dB	6.1dB	
No.3 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.2dB	4.4dB	5.9dB	6.1dB	
No.4 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.2dB	4.4dB	5.9dB	6.1dB	

*10m/3m = Measurement distance

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

Other test except Conducted Emission and Spurious Emission (Radiated)

The measurement uncertainty for this test is 3.0dB.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	IC4247	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	IC4247-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	IC4247-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	IC4247-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Test instruments and Data of EMI

Refer to APPENDIX 1 to 3.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Modes

The mode used for test :

Test	Mode	Tested frequency
Carrier Frequency Separation	Bluetooth Transmitting (Tx) (Hopping ON) /DH5/3DH5	2402MHz 2441MHz 2480MHz
	Inquiry	2441MHz
20dB Bandwidth	Bluetooth Transmitting (Tx) (Hopping Off)/DH5/3DH5	2402MHz 2441MHz 2480MHz
	Inquiry,	2441MHz
Number of Hopping Frequency	Bluetooth Transmitting (Tx) (Hopping ON)/DH5/3DH5	-
	Inquiry	-
Dwell time	Bluetooth Transmitting (Tx) (Hopping ON) -DH1 -DH3 -DH5 -3DH1 -3DH3 -3DH5	-
	Inquiry	-
Maximum Peak Output Power	Bluetooth Transmitting (Tx) (Hopping Off) -DH5 -2DH5 -3DH5	2402MHz 2441MHz 2480MHz
	Inquiry	2441MHz
Spurious Emission (Conducted/Radiated)	Bluetooth Transmitting (Tx), (Hopping ON)/DH5/3DH5	2402MHz 2441MHz 2480MHz
	Bluetooth Receiving (Rx)	2441MHz
Band Edge Compliance (Conducted)	Bluetooth Transmitting (Tx), DH5/3DH5 -Hopping ON -Hopping OFF	2402MHz 2480MHz
	(Radiated)	Bluetooth Transmitting (Tx), DH5/3DH5 2402MHz 2480MHz
99% Occupied Bandwidth	Bluetooth Transmitting (Tx), DH5/3DH5 -Hopping ON -Hopping OFF	2402MHz 2441MHz 2480MHz

Remarks: Test was not performed at AFH mode, because the decrease of number of channel (min: 20ch) at AFH mode does not influence on the output power, bandwidth, and spurious emission of the EUT. However, the limit level 125mW mode was used due to AFH and EDR mode.

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4.2 Configuration and peripherals

This page has been submitted for a separate exhibit.

SECTION 5: Spurious Emission

[Conducted]

Test Procedure

The Out of Band Emission was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- RBW: 100kHz
- VBW: 300kHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2

Test result : Pass

[Radiated]

Test Procedure

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 80cm above the conducting ground plane.

The Radiated Electric Field Strength intensity has been measured in a Semi Anechoic Chamber with a ground plane and at a distance of 3m(Below 10GHz) and 1m(Upper 10GHz).

The height of the measuring varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

In any 100kHz bandwidth outside the frequency band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 2 of RSS-210 2.7 (IC) and outside the restricted band of FCC15.205 / Table 1 of RSS-210 2.7 (IC).

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver / Spectrum Analyzer	Spectrum Analyzer
Detector	QP: BW 120kHz(T/R)	PK: RBW:1MHz/VBW: 1MHz
IF Bandwidth	20dBc : RBW: 100kHz VBW: 300kHz (S/A)	AV: RBW:1MHz/VBW:10Hz 20dBc : RBW:100kHz/VBW:300kHz

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Test data : APPENDIX 2

Test result : Pass

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SECTION 6: Bandwidth

Test Procedure

The bandwidth was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- Span: 3MHz
- RBW: 30kHz
- VBW: 30kHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass

SECTION 7: Maximum Peak Output Power

Test Procedure

The Maximum Peak Output Power was measured with a power meter (tested bandwidth: 50MHz) connected to the antenna port.

Test data : APPENDIX 2
Test result : Pass

SECTION 8: Carrier Frequency Separation

Test Procedure

The carrier frequency separation was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- Span: 3MHz
- RBW: 100kHz
- VBW: 300kHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass

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SECTION 9: Number of Hopping Frequency

Test Procedure

The Number of Hopping Frequency was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- Span: 30MHz
- RBW: 300kHz
- VBW: 1MHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass

SECTION 10: Dwell time

Test Procedure

The Dwell time was measured with a spectrum analyzer connected to the antenna port.
The following spectrum analyzer setting was used:

- Span: Zero Span
- RBW: 1MHz
- VBW: 1MHz
- Sweep: as necessary to capture the entire dwell time per hopping channel
- Detector: function peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass